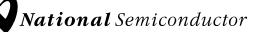
#### July 2001



### DS90CR287/DS90CR288A +3.3V Rising Edge Data Strobe LVDS 28-Bit Channel Link-85 MHZ

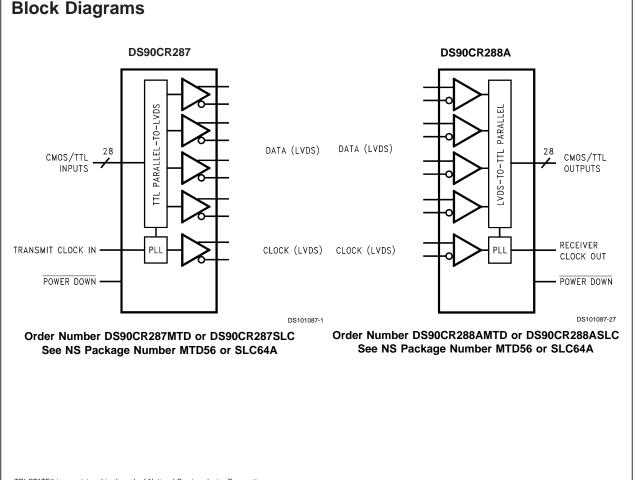
#### **General Description**

The DS90CR287 transmitter converts 28 bits of LVCMOS/ LVTTL data into four LVDS (Low Voltage Differential Signaling) data streams. A phase-locked transmit clock is transmitted in parallel with the data streams over a fifth LVDS link. Every cycle of the transmit clock 28 bits of input data are sampled and transmitted. The DS90CR288A receiver converts the four LVDS data streams back into 28 bits of LVCMOS/LVTTL data. At a transmit clock frequency of 85 MHZ, 28 bits of TTL data are transmitted at a rate of 595 Mbps per LVDS data channel. Using a 85 MHZ clock, the data throughput is 2.38 Gbit/s (297.5 Mbytes/sec). Both devices are also offered in 64 ball, 0.8mm fine pitch ball grid array (FBGA) package which provides a 44 % reduction in PCB footprint over the 56L TSSOP package.

This chipset is an ideal means to solve EMI and cable size problems associated with wide, high-speed TTL interfaces.

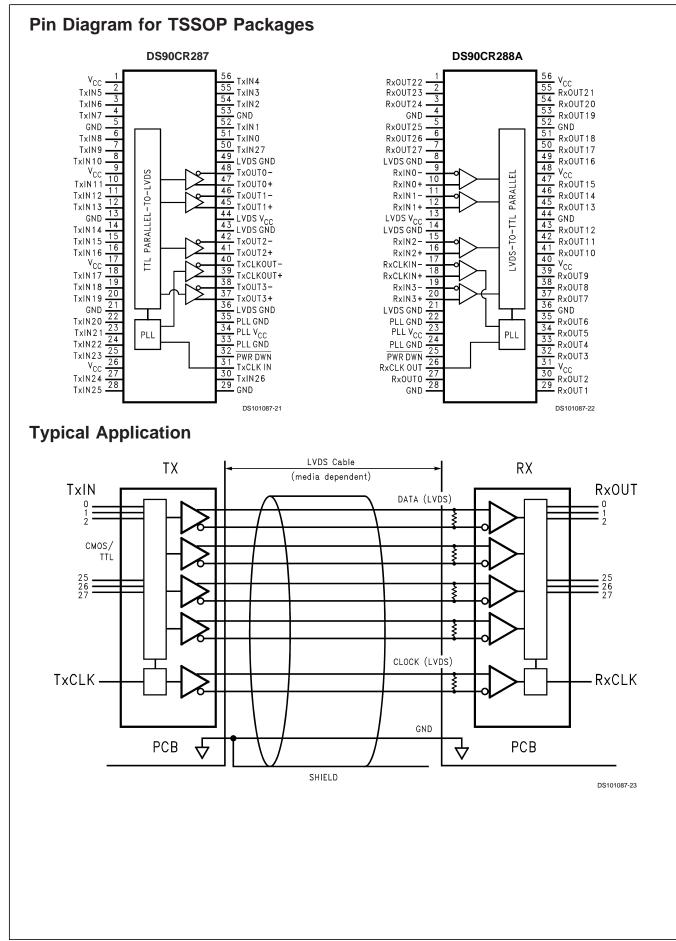
#### Features

- 20 to 85 MHZ shift clock support
- 50% duty cycle on receiver output clock
- 2.5 / 0 ns Set & Hold Times on TxINPUTs
- Low power consumption
- ±1V common mode range (around +1.2V)
- Narrow bus reduces cable size and cost
- Up to 2.38 Gbps throughput
- Up to 297.5 Megabytes/sec bandwidth
- 345 mV (typ) swing LVDS devices for low EMI
- PLL requires no external components
- Rising edge data strobe
- Compatible with TIA/EIA-644 LVDS standard
- Low profile 56-lead TSSOP package
- Both devices are also available in 64 ball, 0.8mm fine pitch ball grid array (FBGA) package



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# DS90CR287/DS90CR288A

#### Absolute Maximum Ratings (Note 1)

If Military/Aerospace specified devices are required, please contact the National Semiconductor Sales Office/ Distributors for availability and specifications.

Supply Voltage (V <sub>CC</sub> )	-0.3V to +4V
CMOS/TTL Input Voltage	-0.5V to (V <sub>CC</sub> + 0.3V)
CMOS/TTL Output Voltage	-0.3V to (V <sub>CC</sub> + 0.3V)
LVDS Receiver Input Voltage	-0.3V to (V <sub>CC</sub> + 0.3V)
LVDS Driver Output Voltage	-0.3V to (V <sub>CC</sub> + 0.3V)
LVDS Output Short Circuit	
Duration	Continuous
Junction Temperature	+150°C
Storage Temperature	–65°C to +150°C
Lead Temperature	
(Soldering, 4 sec.)	+260°C
Solder Reflow Temperature	
(20 sec for FBGA)	+220°C
Maximum Package Power Dissip	pation @ +25°C
MTD56 (TSSOP) Package:	
DS90CR287MTD	1.63 W
DS90CR288AMTD	1.61 W
Package Derating:	
DS90CR287MTD	12.5 mW/°C above +25°C

12.4 mW/°C above +25°C
2.0 W
2.0 W
10.2 mW/°C above +25°C
10.2 mW/°C above +25°C
> 7kV
> 700V
> ±300mA

## Recommended Operating Conditions

	Min	Nom	Max	Units
Supply Voltage (V <sub>CC</sub> )	3.0	3.3	3.6	V
Operating Free Air				
Temperature (T <sub>A</sub> )	-10	+25	+70	°C
Receiver Input Range	0		2.4	V
Supply Noise Voltage ( $V_{CC}$ )			100	$mV_{PP}$

#### **Electrical Characteristics**

Over recommended operating supply and temperature ranges unless otherwise specified

Symbol	Parameter	Conditions	Min	Тур	Max	Units
LVCMOS	S/LVTTL DC SPECIFICATIONS	•		•	•	•
V <sub>IH</sub>	High Level Input Voltage		2.0		V <sub>cc</sub>	V
V <sub>IL</sub>	Low Level Input Voltage		GND		0.8	V
V <sub>OH</sub>	High Level Output Voltage	$I_{OH} = -0.4 \text{ mA}$	2.7	3.3		V
V <sub>OL</sub>	Low Level Output Voltage	I <sub>OL</sub> = 2 mA		0.06	0.3	V
V <sub>CL</sub>	Input Clamp Voltage	$I_{CL} = -18 \text{ mA}$		-0.79	-1.5	V
I <sub>IN</sub>	Input Current	$V_{IN} = 0.4V, 2.5V \text{ or } V_{CC}$		+1.8	+15	μA
		V <sub>IN</sub> = GND	-10	0		μA
l <sub>os</sub>	Output Short Circuit Current	V <sub>OUT</sub> = 0V		-60	-120	mA
LVDS DI	RIVER DC SPECIFICATIONS					
V <sub>OD</sub>	Differential Output Voltage	$R_{L} = 100\Omega$	250	290	450	mV
$\Delta V_{OD}$	Change in V <sub>OD</sub> between Complimentary Output States				35	mV
Vos	Offset Voltage (Note 4)		1.125	1.25	1.375	V
$\Delta V_{OS}$	Change in V <sub>OS</sub> between Complimentary Output States				35	mV
l <sub>os</sub>	Output Short Circuit Current	$V_{OUT} = 0V, R_L = 100\Omega$		-3.5	-5	mA
I <sub>oz</sub>	Output TRI-STATE <sup>®</sup> Current	$\overline{PWR\;DWN}=0V,$		±1	±10	μA
		$V_{OUT} = 0V \text{ or } V_{CC}$				
LVDS RI	ECEIVER DC SPECIFICATIONS	•			•	·
V <sub>TH</sub>	Differential Input High Threshold	$V_{CM} = +1.2V$			+100	mV
V <sub>TL</sub>	Differential Input Low Threshold	]	-100			mV
I <sub>IN</sub>	Input Current	$V_{IN} = +2.4V, V_{CC} = 3.6V$			±10	μA
		$V_{IN} = 0V, V_{CC} = 3.6V$			±10	μA

#### Electrical Characteristics (Continued)

Over recommended operating supply and temperature ranges unless otherwise specified

Symbol	Parameter	Conditions		Min	Тур	Max	Units
TRANS	AITTER SUPPLY CURRENT						
I <sub>CCTW</sub>	Transmitter Supply Current	$R_{L} = 100\Omega,$	f = 33 MHz		31	45	mA
	Worst Case (with Loads)	$C_L = 5 \text{ pF},$	f = 40 MHz		32	50	mA
		Worst Case Pattern	f = 66 MHz		37	55	mA
		(Figures 1, 2)	f = 85 MHz		42	60	mA
I <sub>CCTZ</sub>	Transmitter Supply Current Power Down	PWR DWN = Low           Driver Outputs in TRI-STATE           under Powerdown Mode			10	55	μA
RECEIV	ER SUPPLY CURRENT				•		
I <sub>CCRW</sub>	Receiver Supply Current Worst	C <sub>L</sub> = 8 pF, Worst Case Pattern ( <i>Figures 1, 3</i> )	f = 33 MHz		49	70	mA
	Case		f = 40 MHz		53	75	mA
			f = 66 MHz		81	114	mA
			f = 85 MHz		96	135	mA
I <sub>CCRZ</sub>	Receiver Supply Current Power Down	PWR DWN = Low Receiver Outputs Stay Low during Powerdown Mode			140	400	μA

Note 1: "Absolute Maximum Ratings" are those values beyond which the safety of the device cannot be guaranteed. They are not meant to imply that the device should be operated at these limits. The tables of "Electrical Characteristics" specify conditions for device operation.

Note 2: Typical values are given for V\_{CC} = 3.3V and T\_A = +25  $^\circ\text{C}.$ 

Note 3: Current into device pins is defined as positive. Current out of device pins is defined as negative. Voltages are referenced to ground unless otherwise specified (except  $V_{OD}$  and  $\Delta V_{OD}$ ).

Note 4:  $V_{\text{OS}}$  previously referred as  $V_{\text{CM}}.$ 

#### **Transmitter Switching Characteristics**

Over recommended operating supply and temperature ranges unless otherwise specified

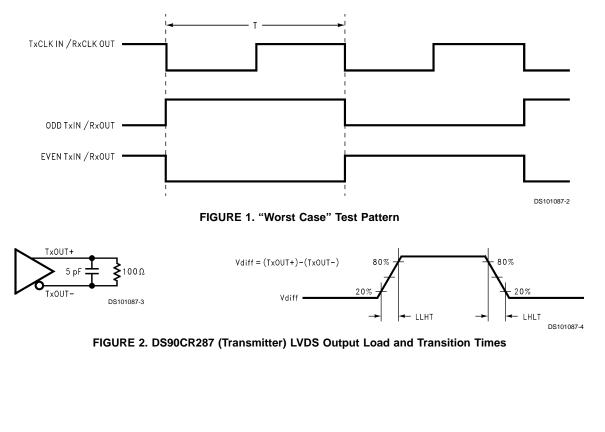
Symbol	Parameter		Min	Тур	Max	Units
LLHT	LVDS Low-to-High Transition Time (Figure 2)			0.75	1.5	ns
LHLT	LVDS High-to-Low Transition Time (Figure 2)			0.75	1.5	ns
TCIT	TxCLK IN Transition Time (Figure 4)		1.0		6.0	ns
TPPos0	Transmitter Output Pulse Position for Bit0 (Figure 14)	) f = 85 MHz		0	0.20	ns
TPPos1	Transmitter Output Pulse Position for Bit1		1.48	1.68	1.88	ns
TPPos2	Transmitter Output Pulse Position for Bit2		3.16	3.36	3.56	ns
TPPos3	Transmitter Output Pulse Position for Bit3		4.84	5.04	5.24	ns
TPPos4	Transmitter Output Pulse Position for Bit4		6.52	6.72	6.92	ns
TPPos5	Transmitter Output Pulse Position for Bit5		8.20	8.40	8.60	ns
TPPos6	Transmitter Output Pulse Position for Bit6		9.88	10.08	10.28	ns
TCIP	TxCLK IN Period (Figure 5)		11.76	Т	50	ns
TCIH	TxCLK IN High Time (Figure 5)		0.35T	0.5T	0.65T	ns
TCIL	TxCLK IN Low Time (Figure 5)		0.35T	0.5T	0.65T	ns
TSTC	TxIN Setup to TxCLK IN (Figure 5)	f = 85 MHz	2.5			ns
THTC	TxIN Hold to TxCLK IN (Figure 5)		0			ns
TCCD	TxCLK IN to TxCLK OUT Delay (Figure 7)	$T_A = 25^{\circ}C,$ $V_{CC} = 3.3V$	3.8		6.3	ns
TPLLS	Transmitter Phase Lock Loop Set (Figure 9)	•			10	ms
TPDD	Transmitter Powerdown Delay (Figure 12)				100	ns
TJIT	TxCLK IN Cycle-to-Cycle Jitter (Input clock requirement)				2	ns

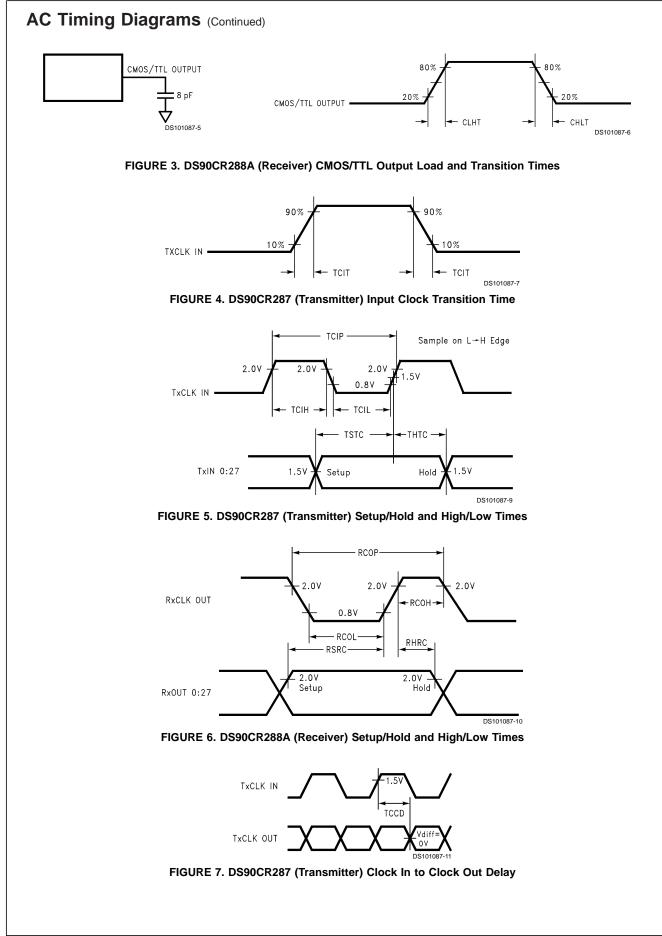
	ver Switching Characteristics mmended operating supply and temperature ranges unless other	erwise specified				
Symbol	Parameter		Min	Тур	Max	Units
CLHT	CMOS/TTL Low-to-High Transition Time (Figure 3)			2	3.5	ns
CHLT	CMOS/TTL High-to-Low Transition Time (Figure 3)			1.8	3.5	ns
RSPos0	Receiver Input Strobe Position for Bit 0 (Figure 15)	f = 85 MHz	0.49	0.84	1.19	ns
RSPos1	Receiver Input Strobe Position for Bit 1	-	2.17	2.52	2.87	ns
RSPos2	Receiver Input Strobe Position for Bit 2		3.85	4.20	4.55	ns
RSPos3	Receiver Input Strobe Position for Bit 3		5.53	5.88	6.23	ns
RSPos4	Receiver Input Strobe Position for Bit 4	7	7.21	7.56	7.91	ns
RSPos5	Receiver Input Strobe Position for Bit 5	1	8.89	9.24	9.59	ns
RSPos6	Receiver Input Strobe Position for Bit 6		10.57	10.92	11.27	ns
RSKM	RxIN Skew Margin (Note 5) (Figure 16)	f = 85 MHz	290			ps
RCOP	RxCLK OUT Period (Figure 6)	≺ OUT Period ( <i>Figure 6</i> )		Т	50	ns
RCOH	RxCLK OUT High Time (Figure 6)	f = 85 MHz	4	5	6.5	ns
RCOL	RxCLK OUT Low Time (Figure 6)	7	3.5	5	6	ns
RSRC	RxOUT Setup to RxCLK OUT (Figure 6)	7	3.5			ns
RHRC	RxOUT Hold to RxCLK OUT (Figure 6)	7	3.5			ns
RCCD	RxCLK IN to RxCLK OUT Delay @ 25°C, V <sub>CC</sub> = 3.3V (Note 6)(Figure 8)		5.5	7	9.5	ns
RPLLS	Receiver Phase Lock Loop Set (Figure 10)				10	ms
RPDD	Receiver Powerdown Delay (Figure 13)				1	μs

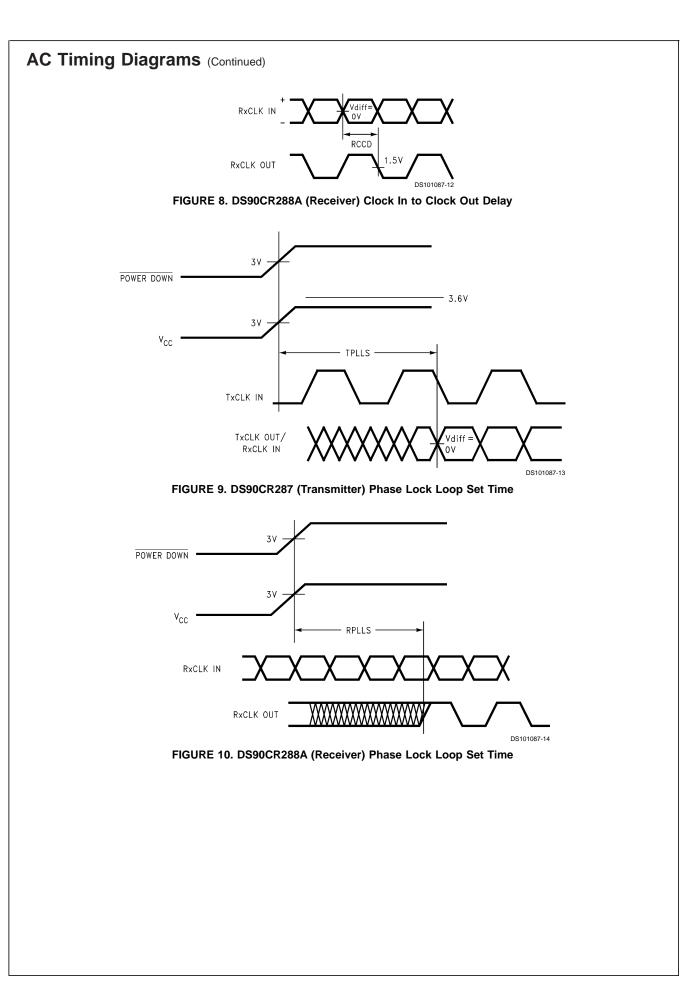
Note 5: Receiver Skew Margin is defined as the valid data sampling region at the receiver inputs. This margin takes into account the transmitter pulse positions (min and max) and the receiver input setup and hold time (internal data sampling window-RSPOS). This margin allows LVDS interconnect skew, inter-symbol interference (both dependent on type/length of cable), and source clock (less than 150 ps).

Note 6: Total latency for the channel link chipset is a function of clock period and gate delays through the transmitter (TCCD) and receiver (RCCD). The total latency for the 217/287 transmitter and 218/288A receiver is: (T + TCCD) + (2\*T + RCCD), where T = Clock period.

#### **AC Timing Diagrams**







DS90CR287/DS90CR288A

#### AC Timing Diagrams (Continued)

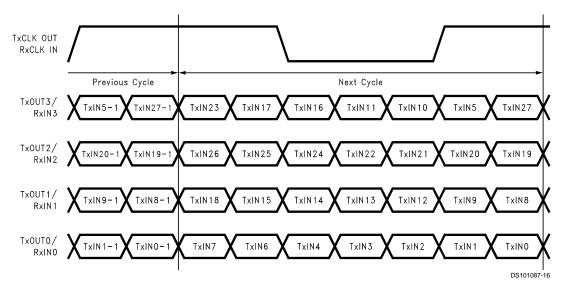


FIGURE 11. 28 Parallel TTL Data Inputs Mapped to LVDS Outputs

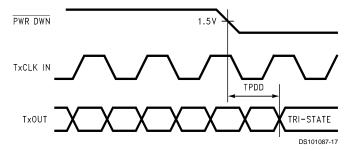


FIGURE 12. Transmitter Powerdown Delay

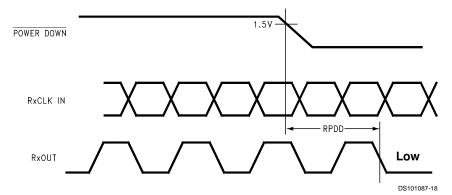
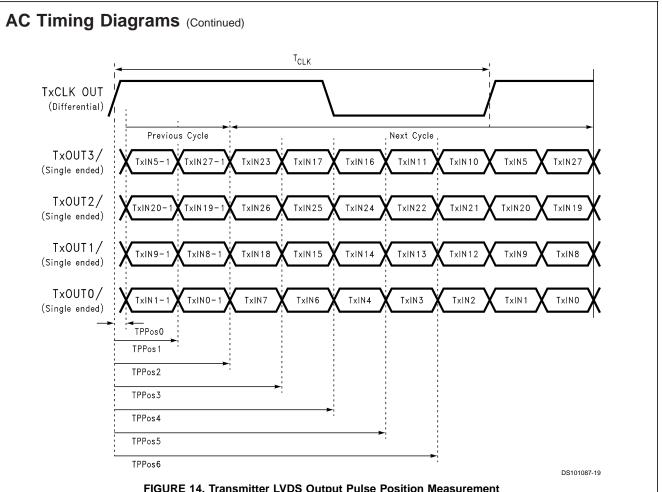
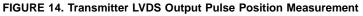
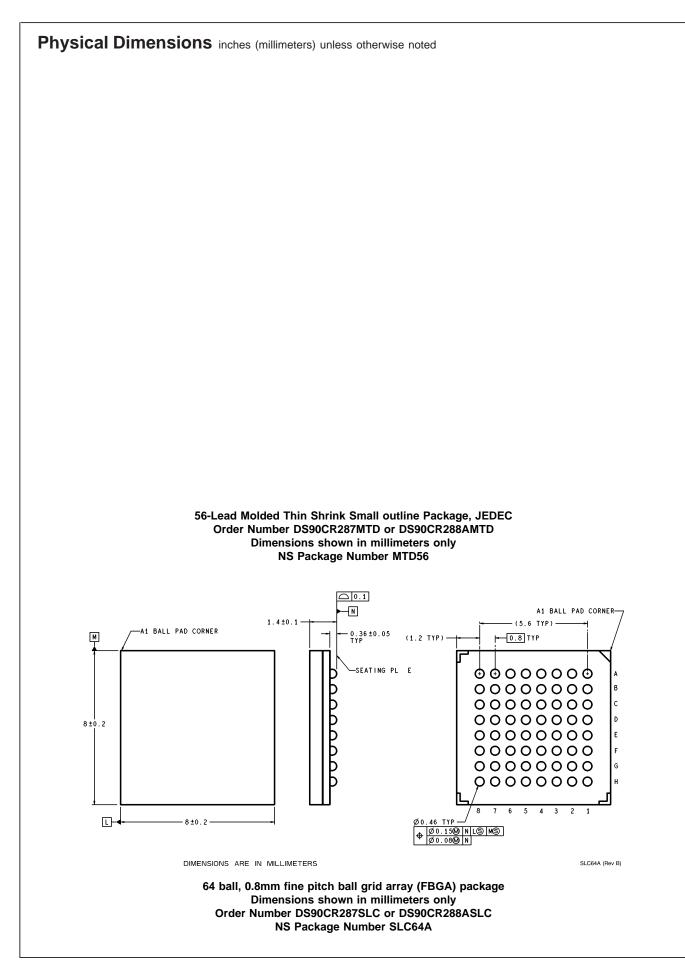


FIGURE 13. Receiver Powerdown Delay





DS90CR287/DS90CR288A



#### Notes

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 National Semiconductor Corporation Americas Email: support@nsc.com
 National Semiconductor Europe

 www.national.com
 Fax: +49 (0) 180-530 85 86 Email: europe.support@nsc.com

 beutsch
 Tel: +49 (0) 69 9508 6208 English

 rel: +44 (0) 870 24 0 2171 Français Tel: +43 (0) 1 41 91 8790

National Semiconductor Asia Pacific Customer Response Group Tel: 65-2544466 Fax: 65-2504466 Email: ap.support@nsc.com National Semiconductor Japan Ltd. Tel: 81-3-5639-7560 Fax: 81-3-5639-7507

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